TITLE:
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AUTHOR(S):
Hu, Xuesong; Lal, Jyotsana; Jiang, Zhang; Sinha, Sunil K.; Narayanan, Suresh; Sandy, Alec; Jiao, Xuesong; Lurio, Laurence B.

CITATION:

ISSUE DATE:
2006-10-20

URL:
http://hdl.handle.net/2433/110585

RIGHT:
Observation of a Low-viscosity Interface Between Immiscible Polymer Layers

Intense Pulsed Neutron Source, Argonne National Laboratory, Argonne, IL-60439, USA.
Xuesong Hu, Jyotsana La
Department of Physics, University of California, San Diego, La Jolla, CA-92093, USA.
Zhang Jiang, Sunil K. Sinha
Advanced Photon Source, Argonne National Laboratory, Argonne, IL-60439, USA.
Suresh Narayanan, Alec Sandy
Department of Physics, Northern Illinois University, DeKalb, IL-60115, USA.
Xuesong Jiao, Laurence B. Lurio

Abstract: X-ray Photon Correlation Spectroscopy (XPCS) was employed in a surface standing wave geometry in order to resolve the thermally diffusive in-plane dynamics at both the surface/vacuum (top) and polymer/polymer (bottom) interfaces of a thin Polystyrene (PS) film on top of Poly(4-bromostyrene) (PBrS) and supported on a Si substrate. The top vacuum interface shows two relaxation modes: one fast and one slow, while the buried polymer-polymer interface shows a single slow mode. The slow mode of the top interface is similar in magnitude and wavevector dependence to the single mode of the buried interface. The dynamics are consistent with a low-viscosity mixed layer between the PS and PBrS and coupling of the capillary wave fluctuations between this layer and the PS.

1 Introduction

Polymer/Polymer interfaces play an important role in the mechanical toughness of polymer blends, adhesion properties in coatings and co-extrusion of polymers. It has been reported that immiscible polymer blends can have viscosities lower than either of their components [1] and recent multilayer co-extrusion experiments indicate that the lower viscosity is due to interfacial slip [2]. Normally, interfaces between immiscible polymers exhibit poor adhesion [3] and this is attributed to weak entanglements between dissimilar polymers at an interface [4]. Dissipation within the interfacial regions can only be indirectly studied with bulk rheological measurements. Most results are in qualitative agreement with theories [4,5,6] that predict fewer chain entanglements near the interface between two immiscible polymers and thus a small interface width with lower viscosity. The lower viscosity at the interface explains slip on application of shear, however existing theories over-predict the slip effect [2]. Here we report on the development of a new technique, employing x-ray photon correlation spectroscopy [7] in a surface standing wave geometry [8,9], which provides a way to resolve the dynamics at buried polymer-polymer interface at nanoscale resolution both parallel and perpendicular to the interface.

2 Results and Discussion

In order to measure XPCS at a buried interface it is crucial to measure scattering from that interface alone, excluding possible scattering from the free surface or polymer-substrate interface. We have solved this problem by directing a coherent x-ray beam onto a polymer bilayer at grazing incidence so that a standing wave is set up in the sample. The phase of this standing wave can be adjusted to have a high intensity at the polymer-polymer interface and simultaneously a node at the polymer-air interface. In addition, at sufficiently grazing incidence angles, the x-rays do not penetrate to the substrate. Thus, the XPCS signal measured in this condition is an indication of the dynamics of the buried interface alone [8,9]. The sample we have chosen for this measurement is a polymer bilayer composed of a 100 nm polystyrene film on top of a 200 nm polybromostyrene film, supported on a Si substrate.
Figure 1: Auto-correlation functions from single and bilayer films at (a) 210°C ($q=0.00405\text{nm}^{-1}$) PS single layer (○) and PBrS single layer (□) (b) 210°C ($q=0.00430\text{nm}^{-1}$) PS/PBrS top layer (▲) and PS/PBrS bottom layer (◆).

Figure 1b shows measured XPCS correlation functions for incident angles $\theta_m=0.140^\circ$ and $\theta_m=0.180^\circ$, obtained from the PS/PBrS/Si film at 210°C. As can be seen from the Figure 1 at a fixed in-plane wavevector $q=4.3 \times 10^3 \text{nm}^{-1}$ [8, 9] the scattering at $\theta_m=0.140^\circ$ is due entirely to the top PS interface, while the scattering at $\theta_m=0.180^\circ$ is dominated by the buried interface. The solid lines in Figure 1 represent the best single or double exponential fits to the measured autocorrelation at fixed value of $q$, $g_2(t)=1+B \exp(-2t/\tau)$, where $B$ is the speckle contrast and $\tau$ is the relaxation time for equilibrium surface height fluctuations. The time constant for buried interface ($\theta_m=0.180^\circ$) is found to be significantly slower than that of the top surface ($\theta_m=0.140^\circ$). The data from top and buried interface of the bilayer is compared to single layers of equivalent thickness at the same temperature (Figure 1a). In conclusion, have implemented a method for measuring diffuse scattering from each of the interfaces within a polymer bilayer, and shown that it is possible to measure XPCS independently at each interface, this has been measured as function of film thickness, wavevector and temperature.

Acknowledgement This work was supported by the U.S. Department of Energy, BES Materials Science, under contract W-31-109-ENG-38.

References